Abstracts

Eye pattern evaluation in high-speed digital systems analysis by using MTL modeling

G. Antonini, J.L. Drewniak, A. Orlandi and V. Ricchiuti. "Eye pattern evaluation in high-speed digital systems analysis by using MTL modeling." 2002 Transactions on Microwave Theory and Techniques 50.7 (Jul. 2002 [T-MTT]): 1807-1815.

A method for simulating the eye pattern of high-speed digital signals propagated on printed circuit boards using multiconductor transmission-line modeling is proposed in this paper. The approach takes into account the frequency-dependent properties of the dielectric materials of the board and of the conductors. The validation is performed by comparing the modeling with measurements taken from the literature, and directly performed on test boards specially design for this study.

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